



Date Created: 2/17/2004  
Date Issued: 3/4/2004  
PCN # 20040704

FORECAST CHANGE NOTIFICATION

This is to inform you that a design and/or process change will be made to the following product(s). This notification is for your information and concurrence. This is a preliminary notification. A final PCN will be issued when qualification is complete and data is available.

If you require data or samples to qualify this change, please contact **Fairchild Semiconductor within 30 days of receipt of this notification.**

If you have any questions concerning this change, please contact:

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PCN Originator

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REL Engineer

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PCN Type: Die Revision

Effectivity

Expected 1st Device Shipment Date: 5/17/2004  
Earliest Year/Work Week of Changed Product: 0421  
(Note: Package marking may differ from this format)

Product ID (Description):

MAN59407

Description of Change:

Change the die from ES-CMHR509 to ED-008UOV to improve the reliability of the display.

Effect of Change:

N/A

Qualification:

Qual/REL Plan Numbers

Additional Qualification Data

No.	Test Item	Test Condition	Test time / Cycles	Sample Size
1	Temperature Cycle	H : + 80°C 15 Min. L : - 40°C 15 Min.	100 Cycles	10 pcs
2	High Temp. Storage	Temp:100°C	1000 Hours	10 pcs
3	Low Temp. Storage	Temp:-55°C	1000 Hours	10 pcs
4	Room Temp. Operating Life Test	Temp:24+/-2°C IF:8mA	1000 Hours	10 pcs
5	High Temp. Operating Life Test	Temp:85°C IF:5mA	1000 Hours	10 pcs

Affected FSIDs  
MAN59407